

Characteristics of the Superconductor-Metal-Insulator transitions in thin $\text{Nb}_x\text{Si}_{1-x}$ films

C.A. Marrache-Kikuchi



COLLABORATORS



Olivier
Crauste



François
Couëdo



Vincent
Humbert



Laurent
Bergé



Louis
Dumoulin

Financed by :

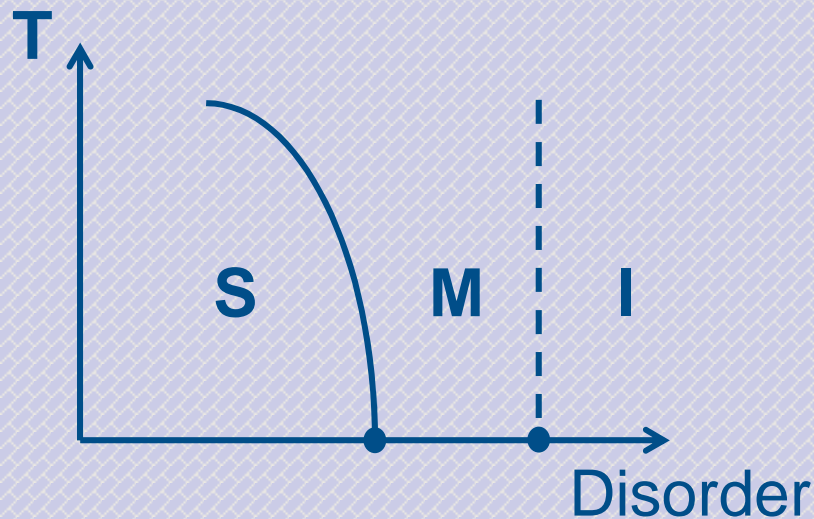


OUTLINE OF THE TALK

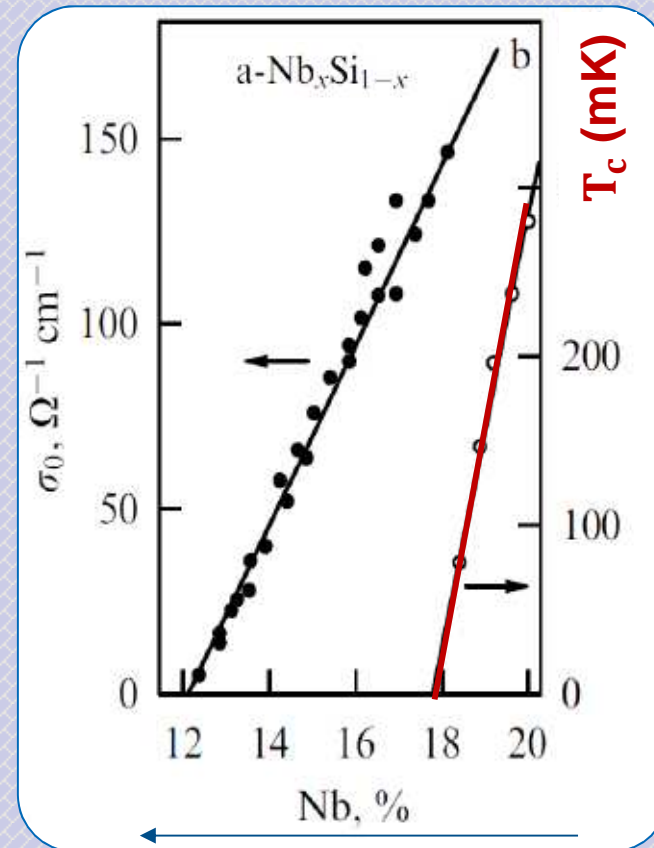
1. Motivation
2. NbSi thin films
 - + System characterization
 - + 3 ways of tuning the disorder
3. Destruction of superconductivity in NbSi films
 - + 2 intermediate metallic phases
4. Onset of the insulating regime

MOTIVATION

i. Superconductor – Metal – Insulator



Possible in 2D ?

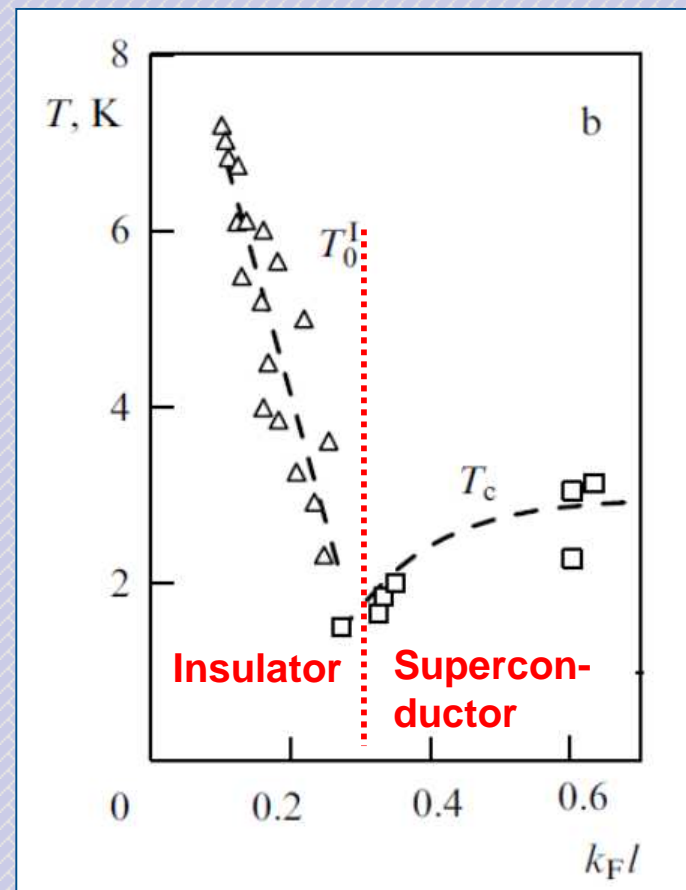
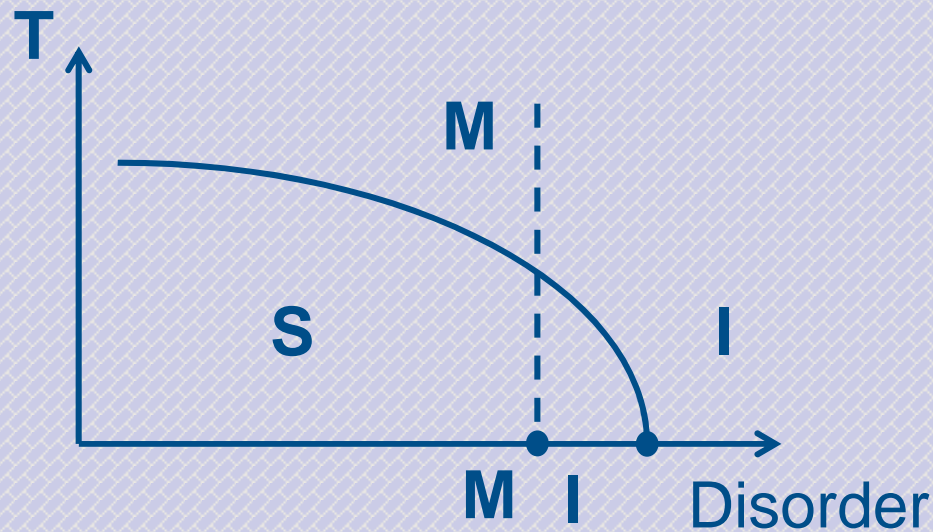


Increasing disorder

Bishop et al., *Sol. St. Elec.*, 28 73 1985

MOTIVATION

ii. Superconductor – Insulator



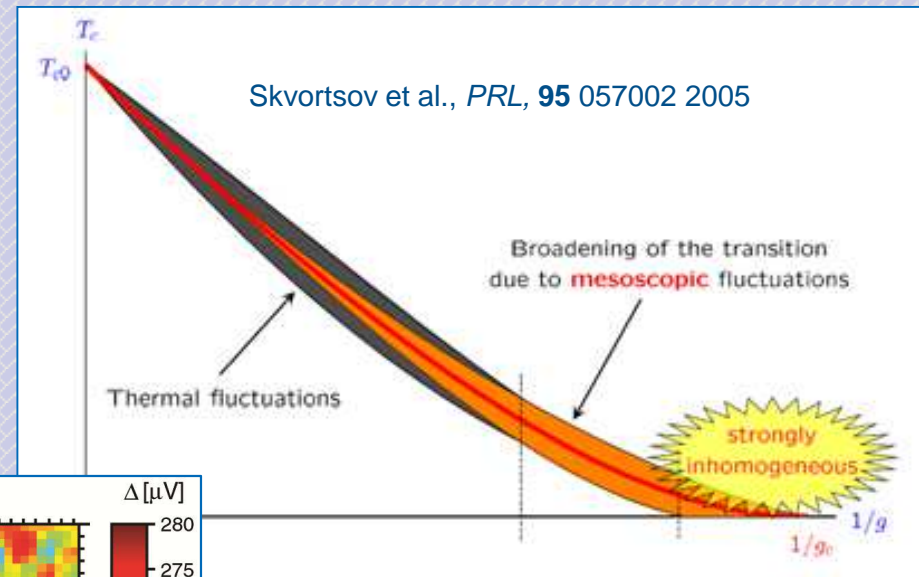
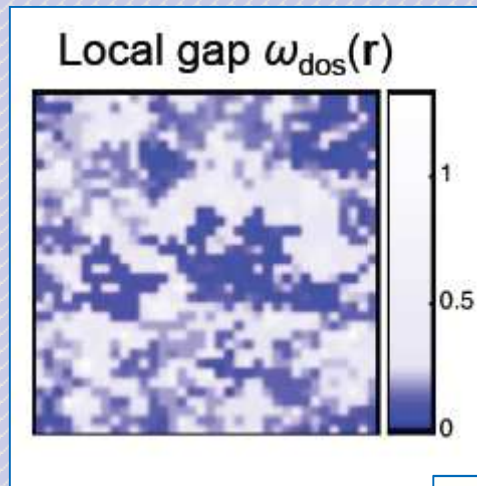
Shahar & Ovadyahu, Phys. Rev. B, 46 10917 1992

← Increasing disorder

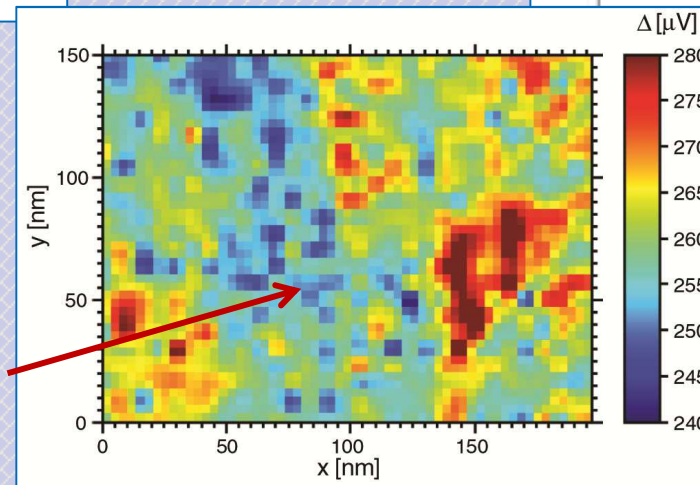
MOTIVATION

iii. Electronic inhomogeneities

Bouadim et al., *Nat. Phys.*, 7 884 2011



Inhomogeneous order parameter



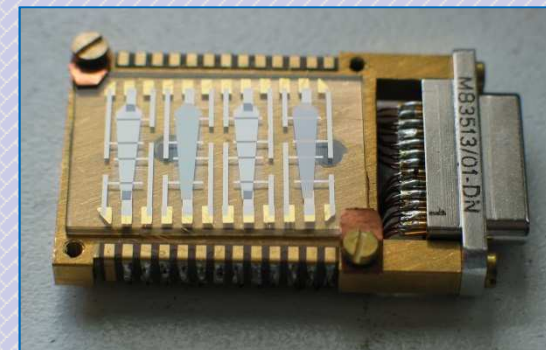
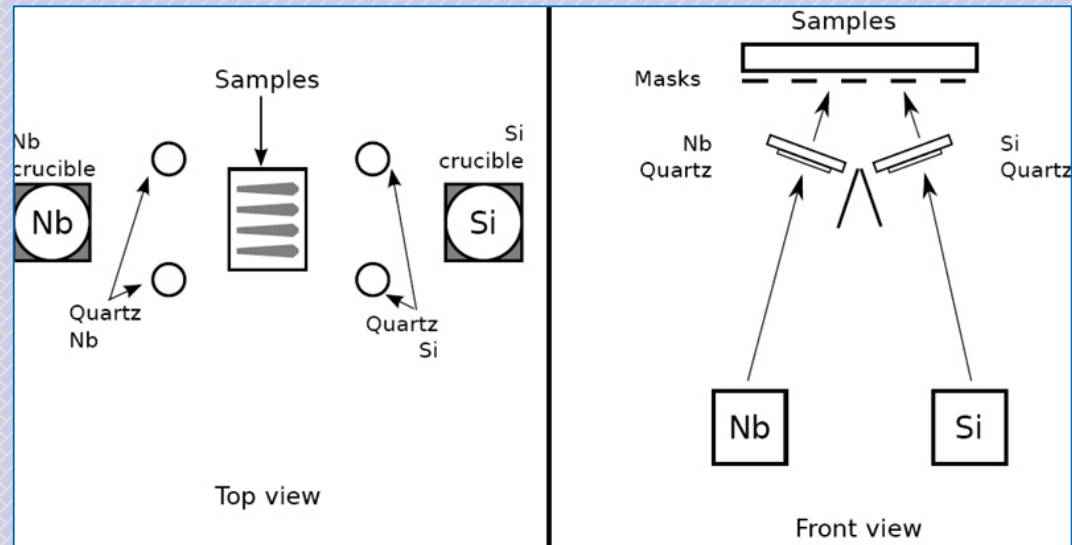
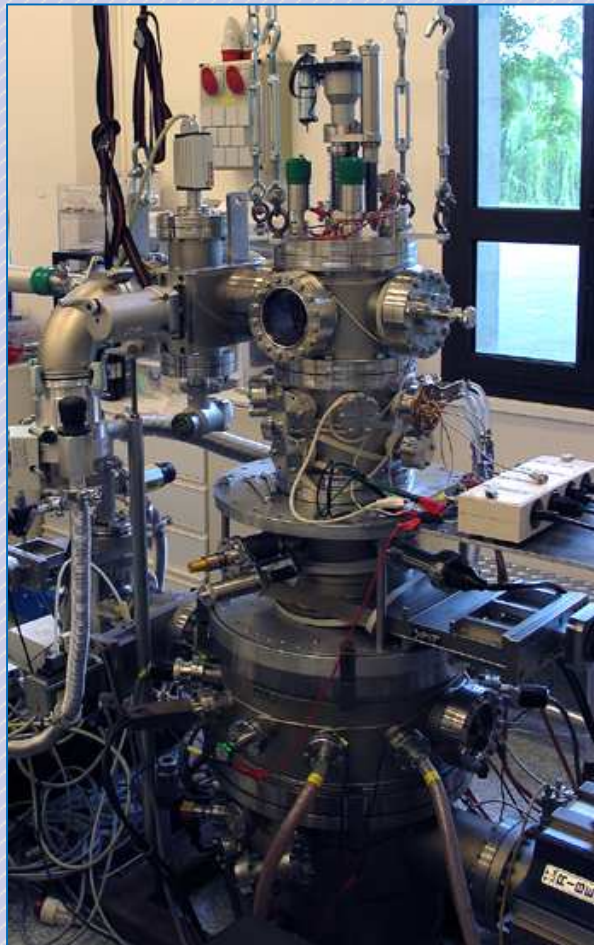
Sacépé et al., *PRL*, 101 157006 2008

A-NBSI THIN FILMS

- **System characterization**
- **3 ways of tuning the disorder**

NBSI THIN FILMS

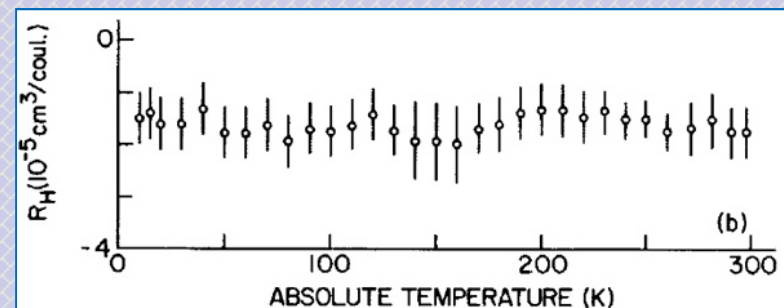
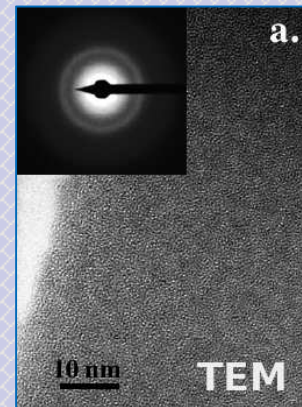
Synthesis



NBSI THIN FILMS

General characteristics

- **Morphology :**
 - Continuous down to 2.5 nm (at least)
 - Amorphous
- **Mean free path** $l = 2.6 \text{ \AA} \text{ to } 5 \text{ \AA}$
- **Electronic density** $n \sim \text{a few } 10^{27} \text{ m}^{-3}$
- **Superconducting coherence length**
 $\xi \sim 50 \text{ nm}$ for $T_c = 1 \text{ K}$
- **Heat treatment :**
 - No modification of n
 - No modification of the composition x



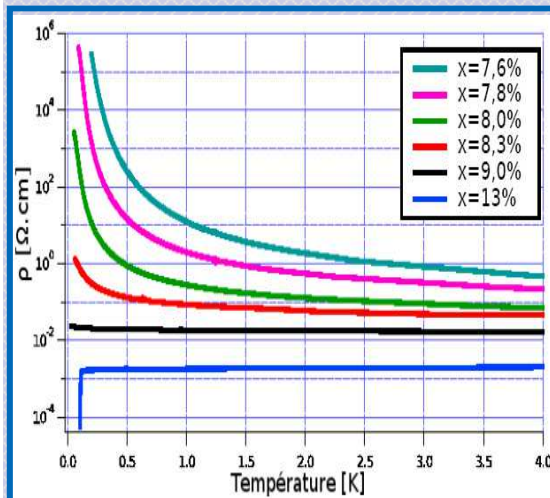
Nava et al., *J. Mat. Res.*, 1 327 1986

NBSI THIN FILMS

3 different disorder-induced SITs

Usual disorder parameter in 2D : $R_{\square} = \frac{\rho}{d_{\perp}} \propto \frac{1}{k_F l}$

Crauste et al. *PRB* **87** 144514 2013

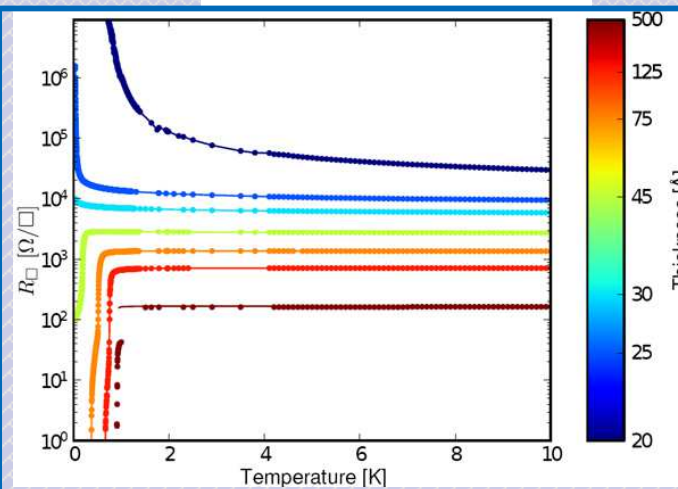


x
induced

Composition

- 3D : $d > 100$ nm

$$R_{\square} = \frac{1}{k_F l}$$

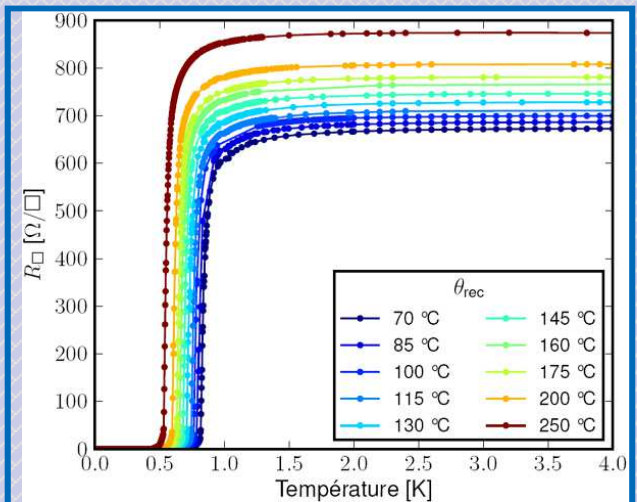


d_{\perp}
induced

Thickness

- 2D, 18%
- $\xi \sim 50$ nm

$$R_{\square} = \frac{\rho}{d}$$



θ_{anneal}
induced

Heat treatment

- $d=12.5$ nm, 18%

$$R_{\square} = \frac{1}{k_F l}$$

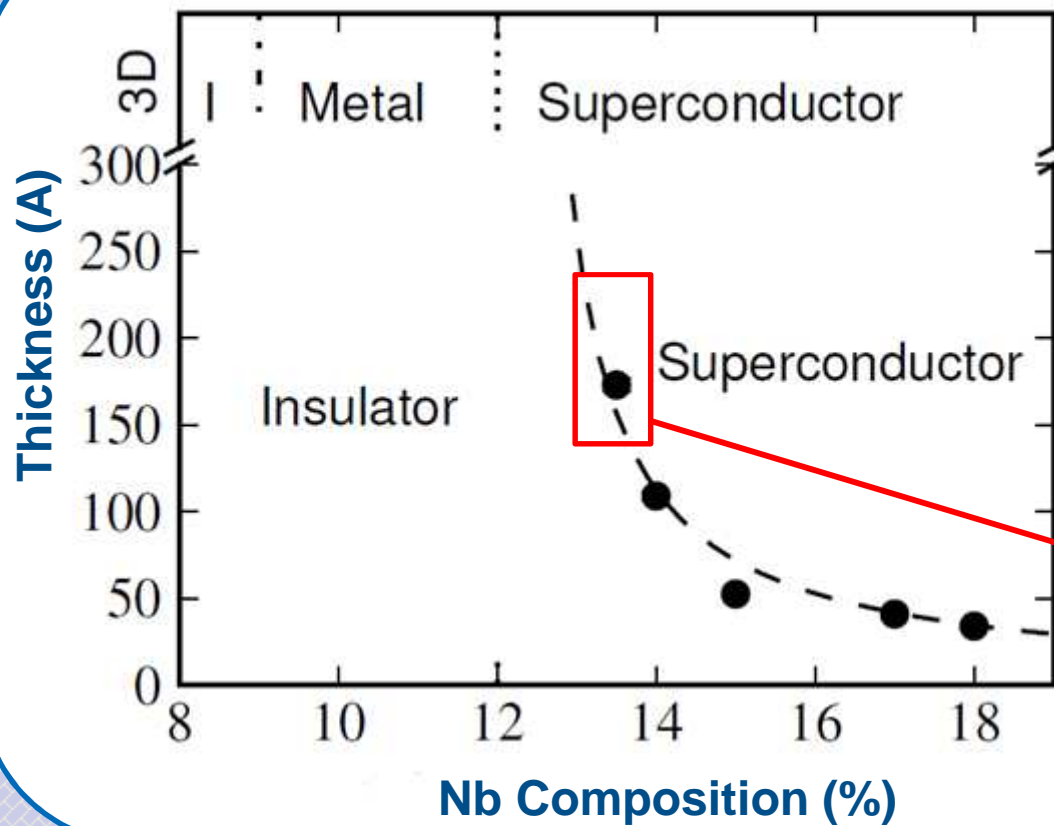
DESTRUCTION OF SUPERCONDUCTIVITY IN NBSI FILMS

- 2 dissipative phases
-

SAMPLES

Near the SIT

Crauste PRB 90 060203 2014

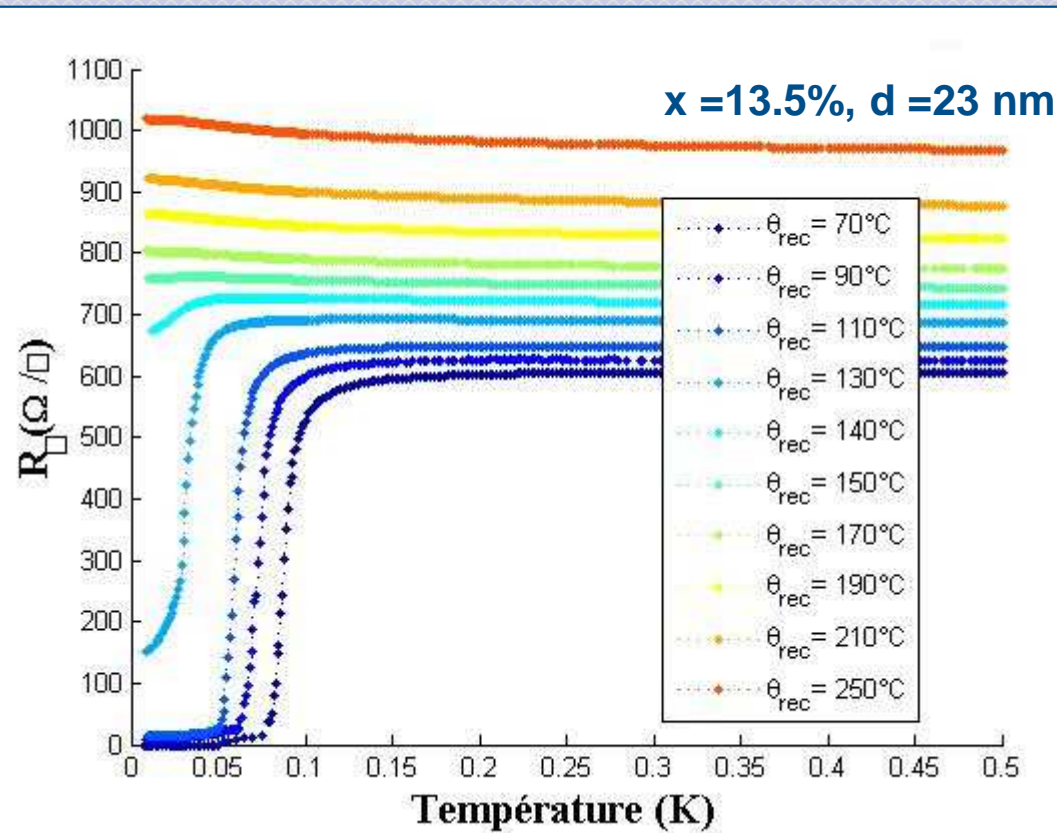


$x = 13.5\%$, $d_c \approx 18$ nm

**4 Films
with $d = [14, 23$ nm]**

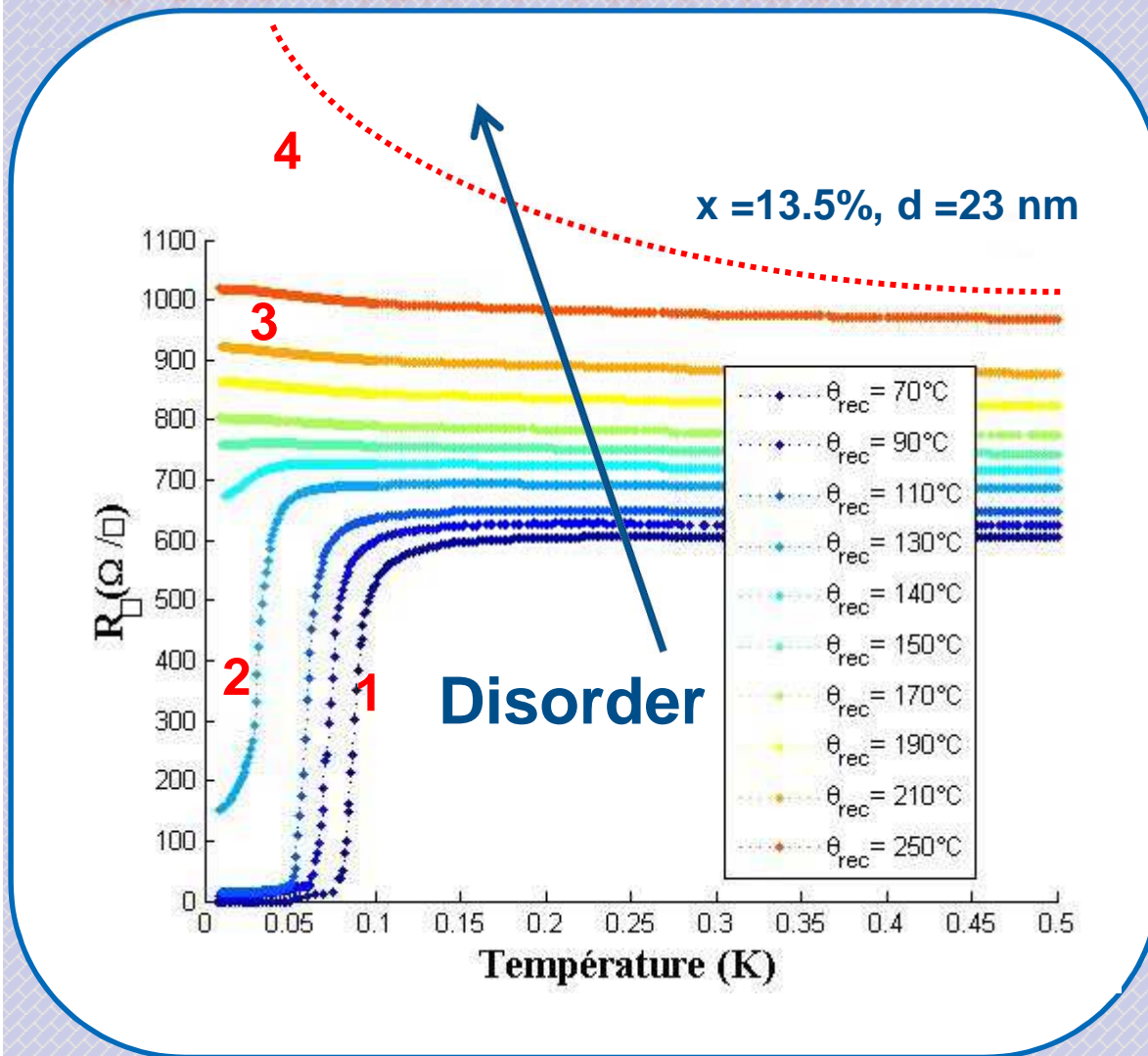
SAMPLES

Fine-tuning the disorder



4 DISTINCT REGIMES

At $T \rightarrow 0$



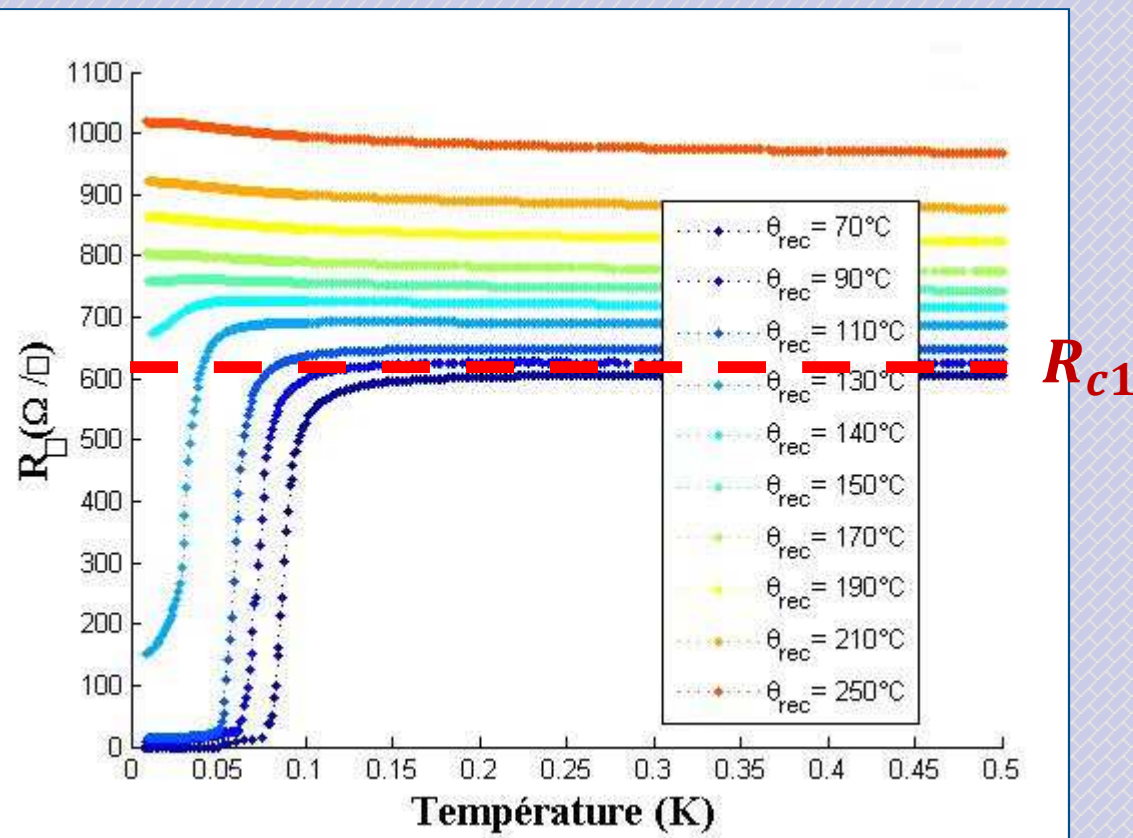
- 1 – Superconductor ($R=0$)
- 2 – Finite R & $TCR > 0$
- 3 – Finite R & $TCR < 0$
- 4 – Insulator

Disorder measured by :

$$R_{\square,N} = R_{\square}(500 \text{ mK})$$

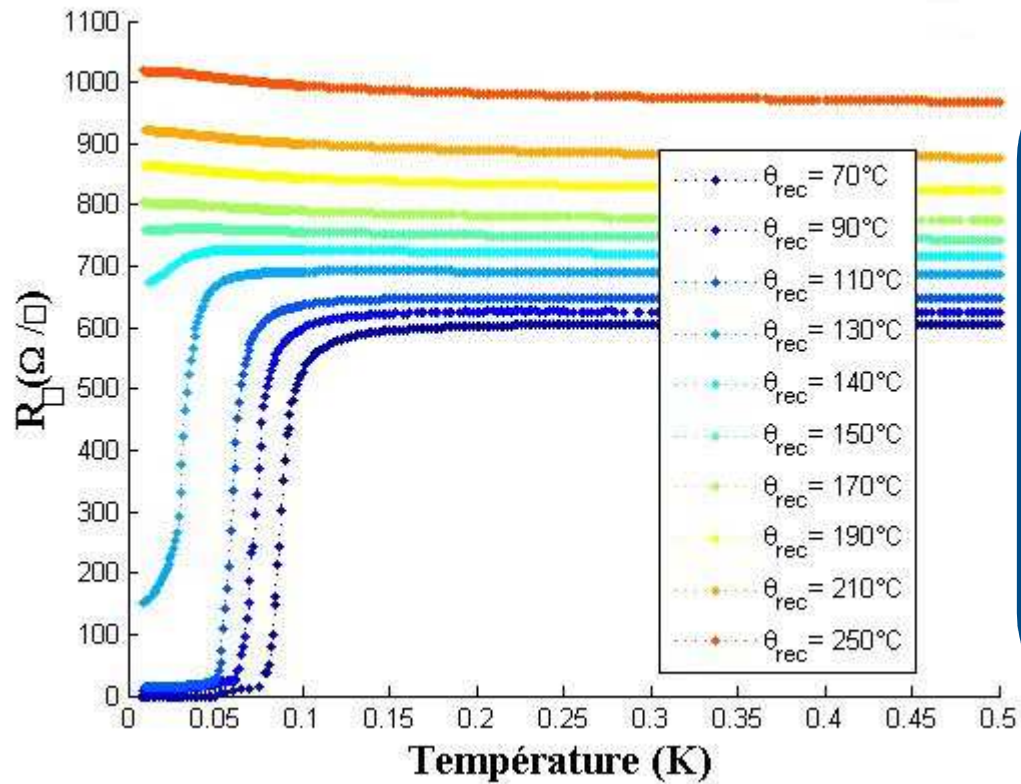
« METAL 1 » PHASE

Superconductor – Metal 1 Transition

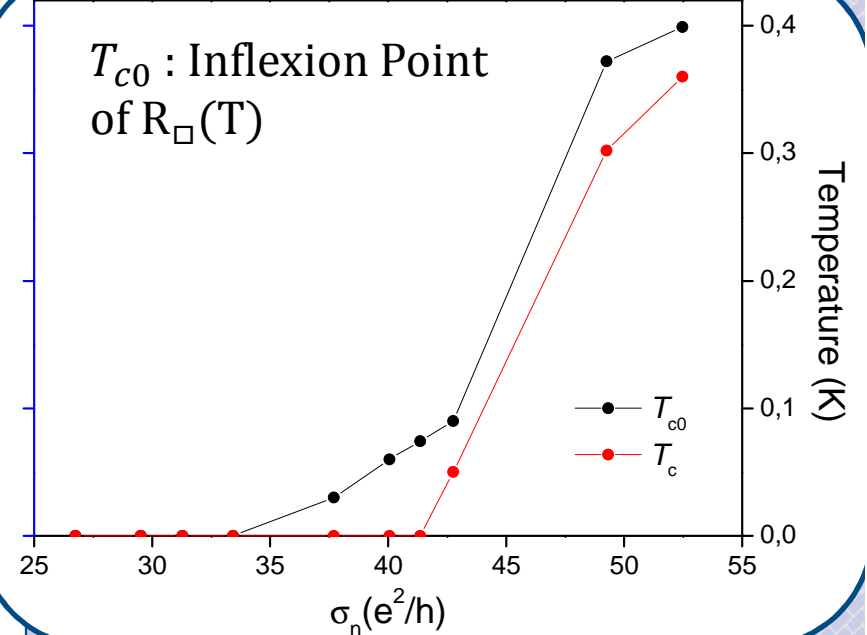


« METAL 1 » PHASE

Energy scale T_{c0}



T_{c0} : Inflexion Point of $R_{\square}(T)$



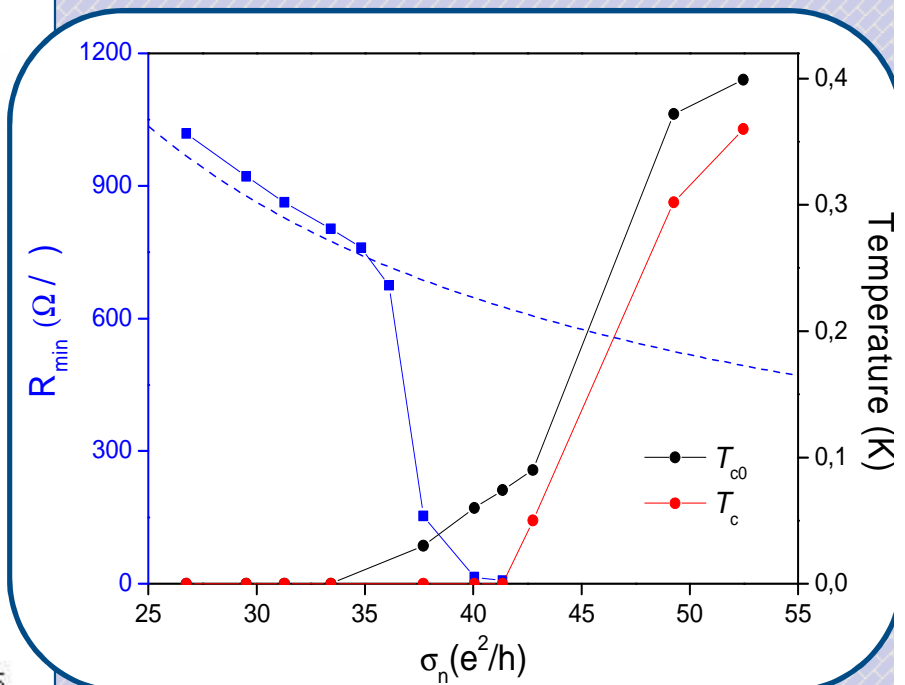
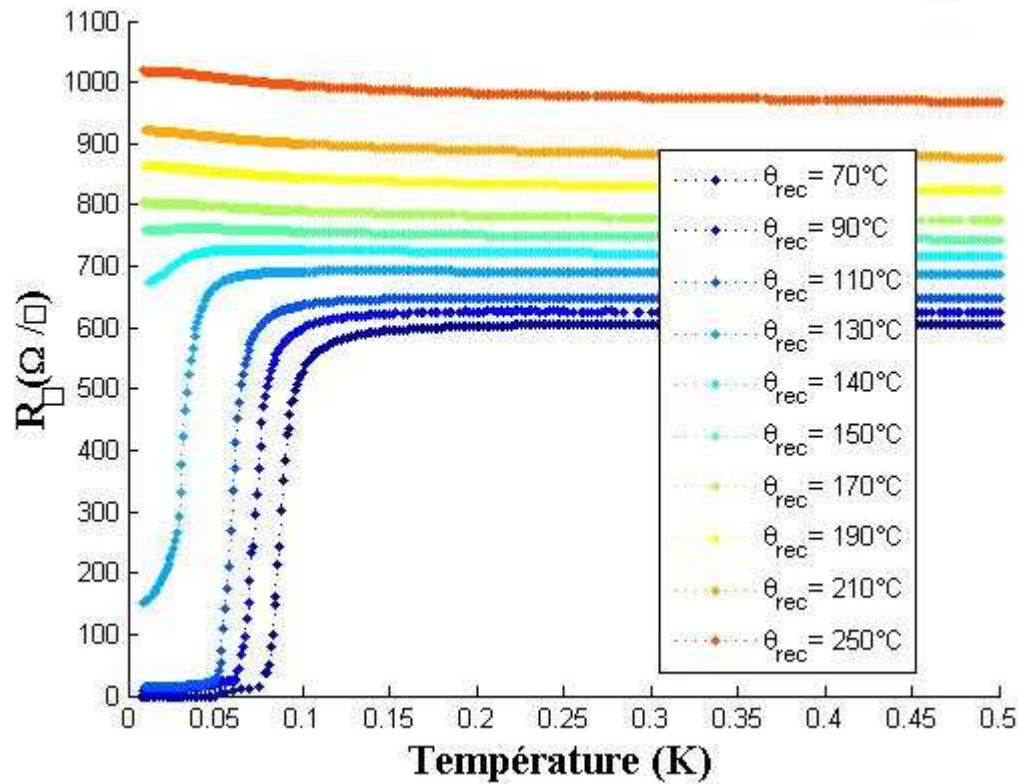
← Increasing disorder

« METAL 1 » PHASE

Minimum resistance

$$R_{\min} = R_{\square}(10 \text{ mK})$$

T_{c0} : Inflexion Point of $R_{\square}(T)$

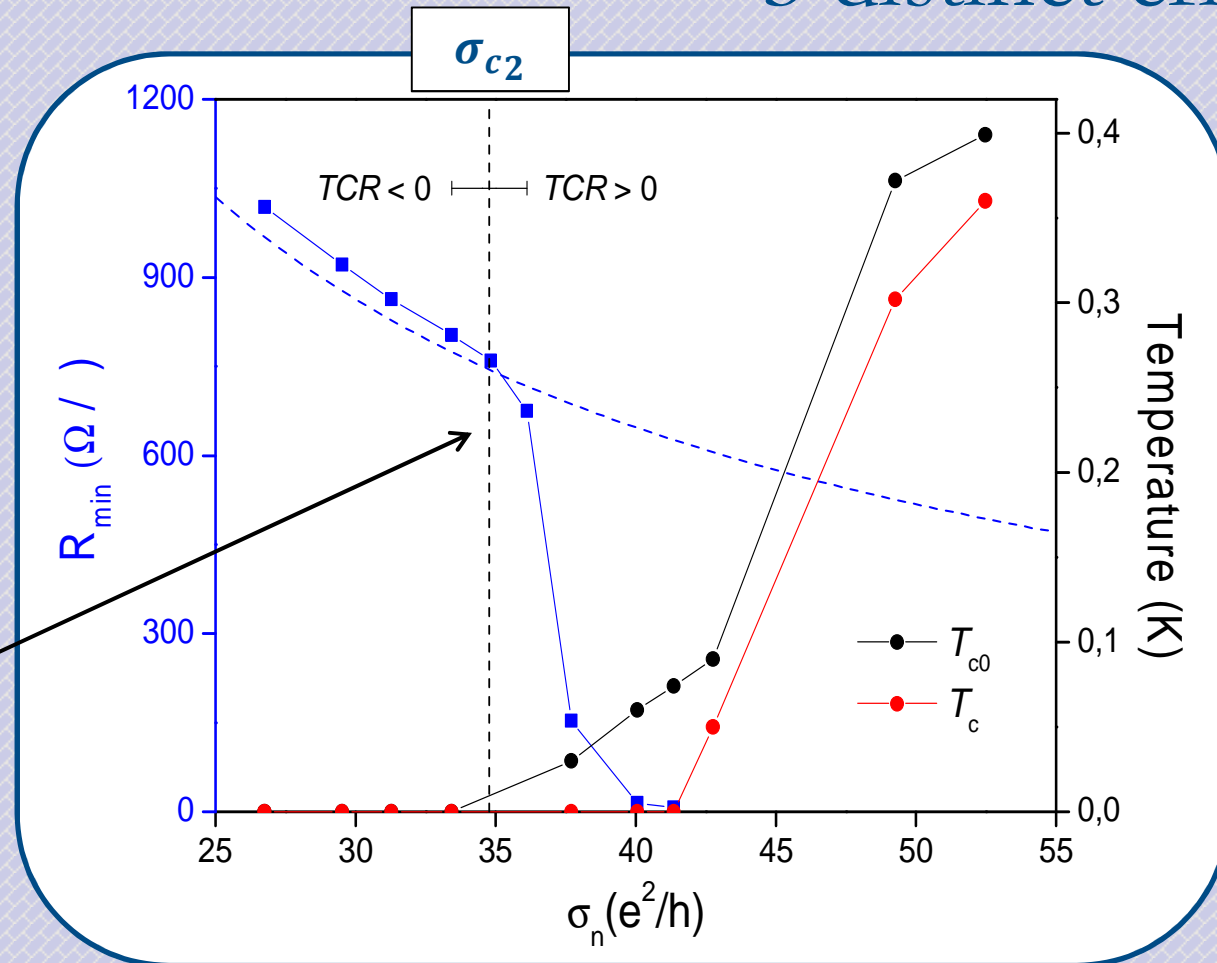


← Increasing disorder

« METAL 1 » - « METAL 2 » TRANSITION

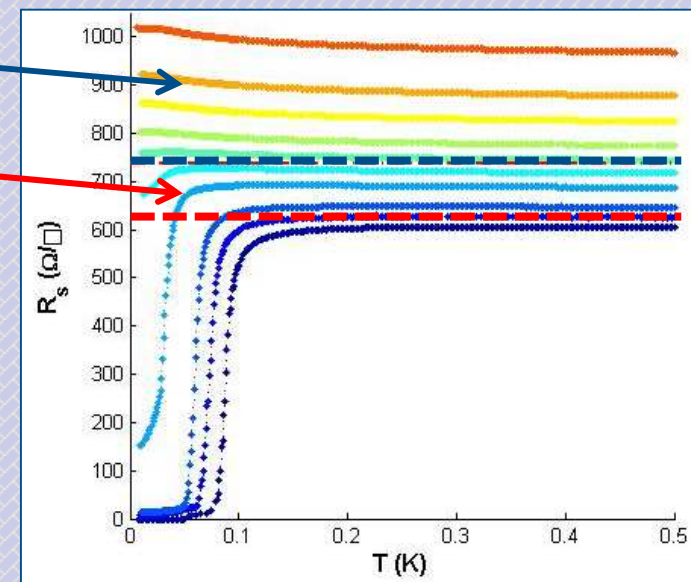
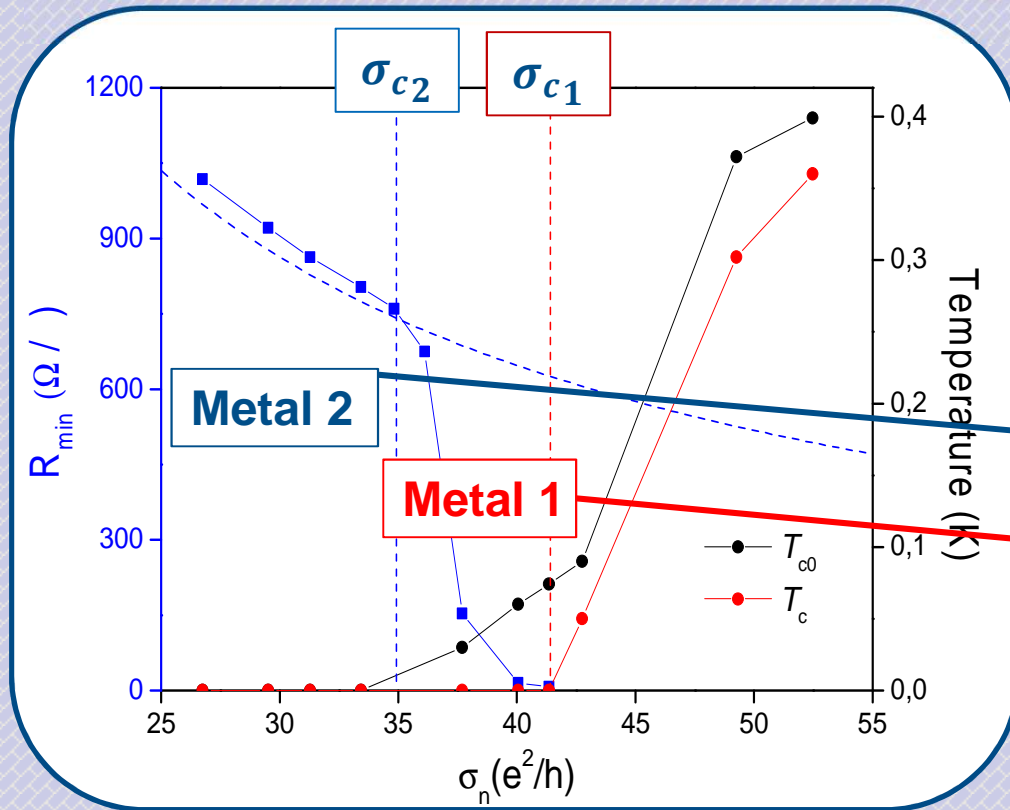
3 distinct criteria

$R_{\min} = R_{\square}(10 \text{ mK})$
 T_{c0} : Inflexion Point



Change of sign of
the $TCR = \frac{dR}{dT}$

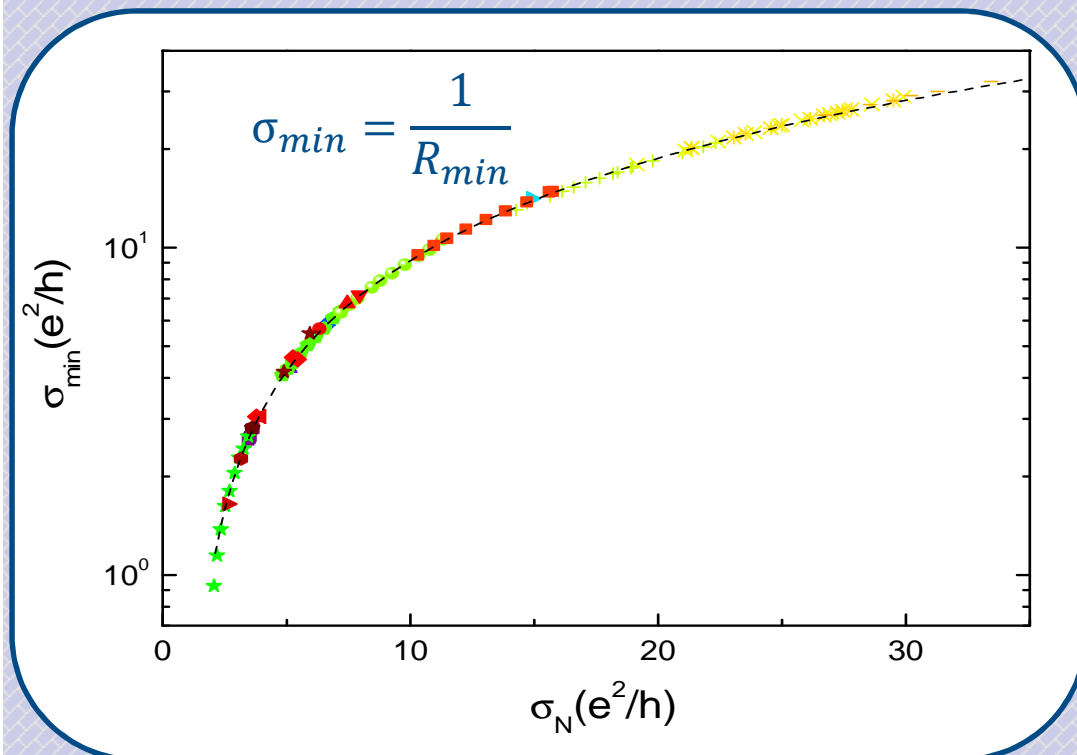
« METAL 1 » - « METAL 2 » TRANSITION



2 dissipative regimes separating the Superconducting and Insulating ground states

« METAL 2 » PHASE

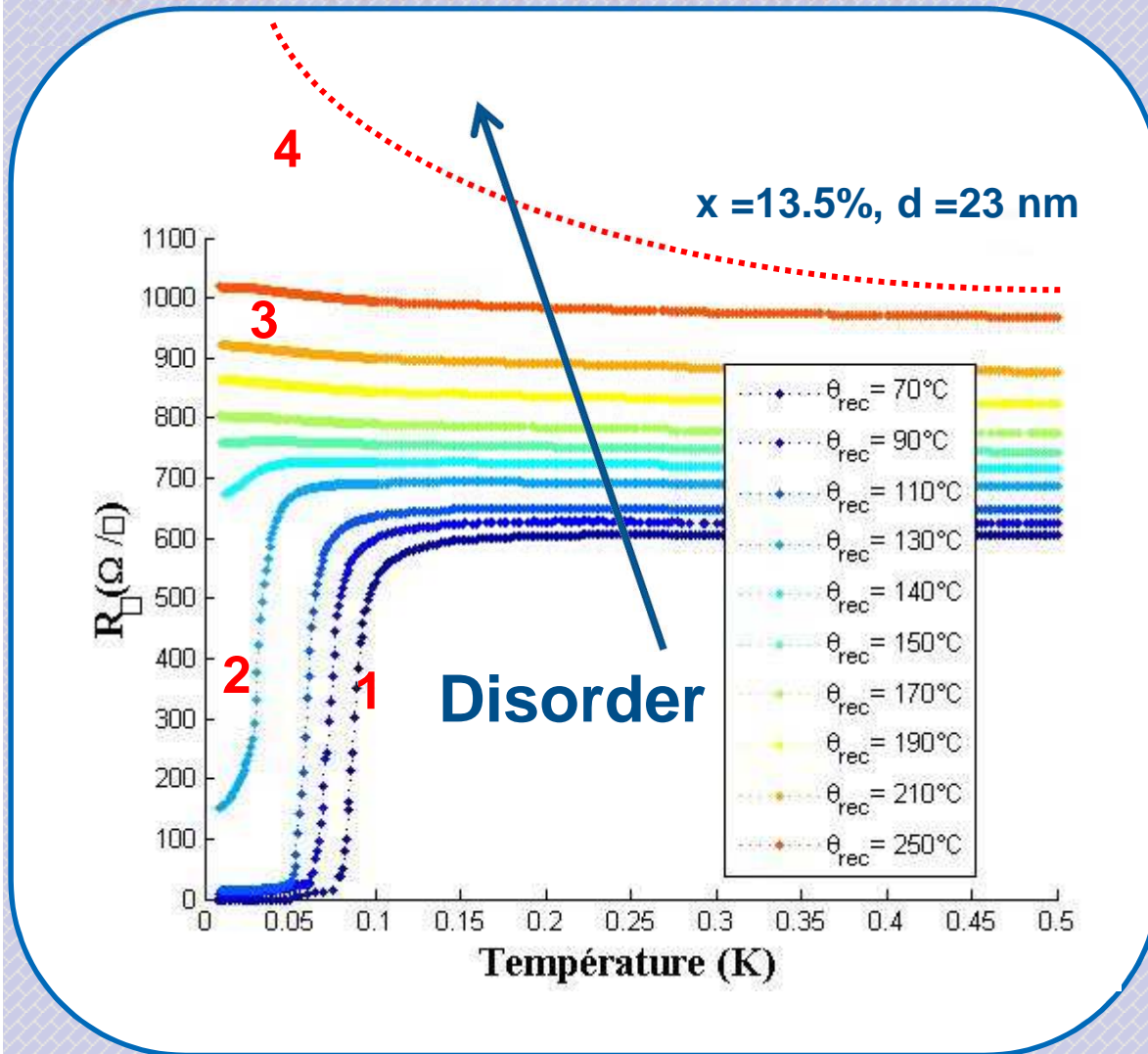
Universal behavior of R_{\min}



- **Universal** behavior (x, d, Θ)
- Vanishing of σ_0 at the Ioffe-Regel limit $k_F l \approx 1$

4 DISTINCT REGIMES

At $T \rightarrow 0$



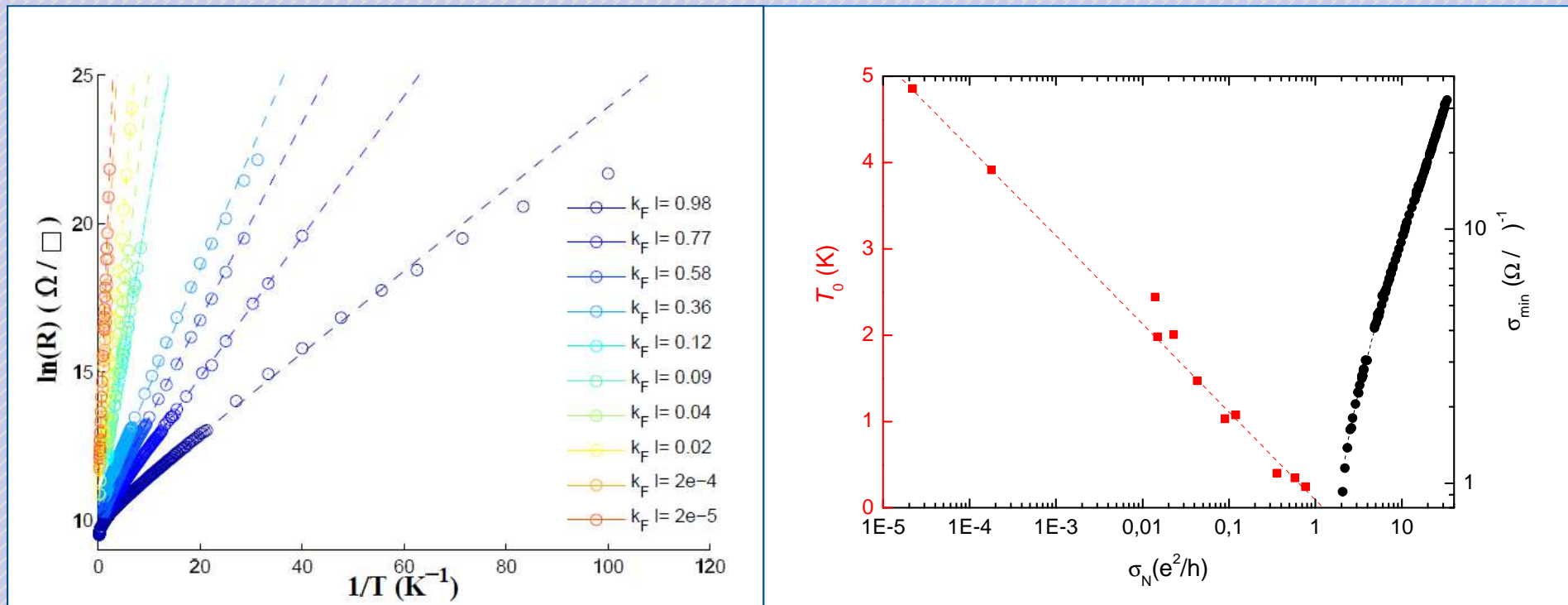
- 1 – Superconductor ($R=0$)
- 2 – Finite R & $TCR > 0$
- 3 – Finite R & $TCR < 0$
- 4 – Insulator

Disorder measured by :

$$R_{\square,N} = R_{\square}(500 \text{ mK})$$

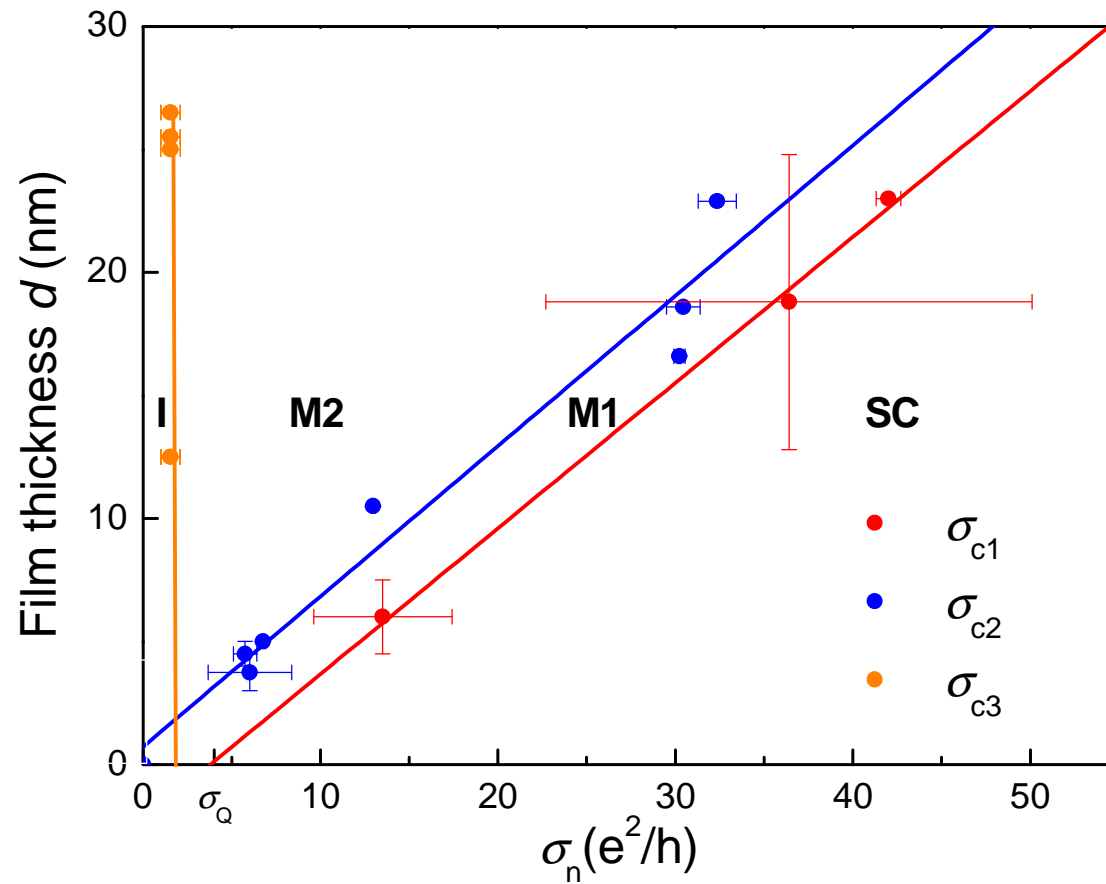
« METAL 2 » - INSULATOR TRANSITION

Energy scale T_0

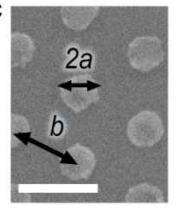
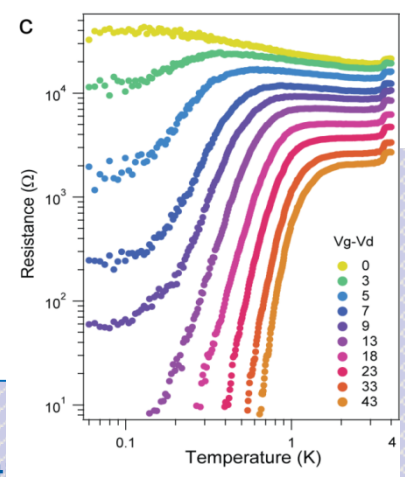
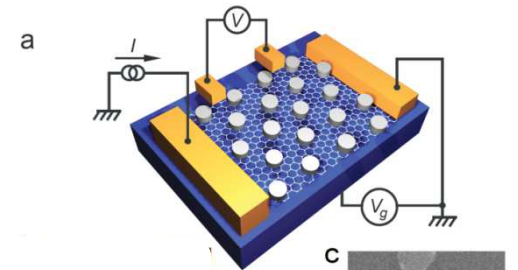
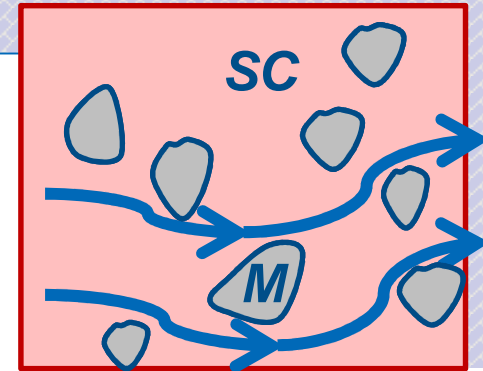
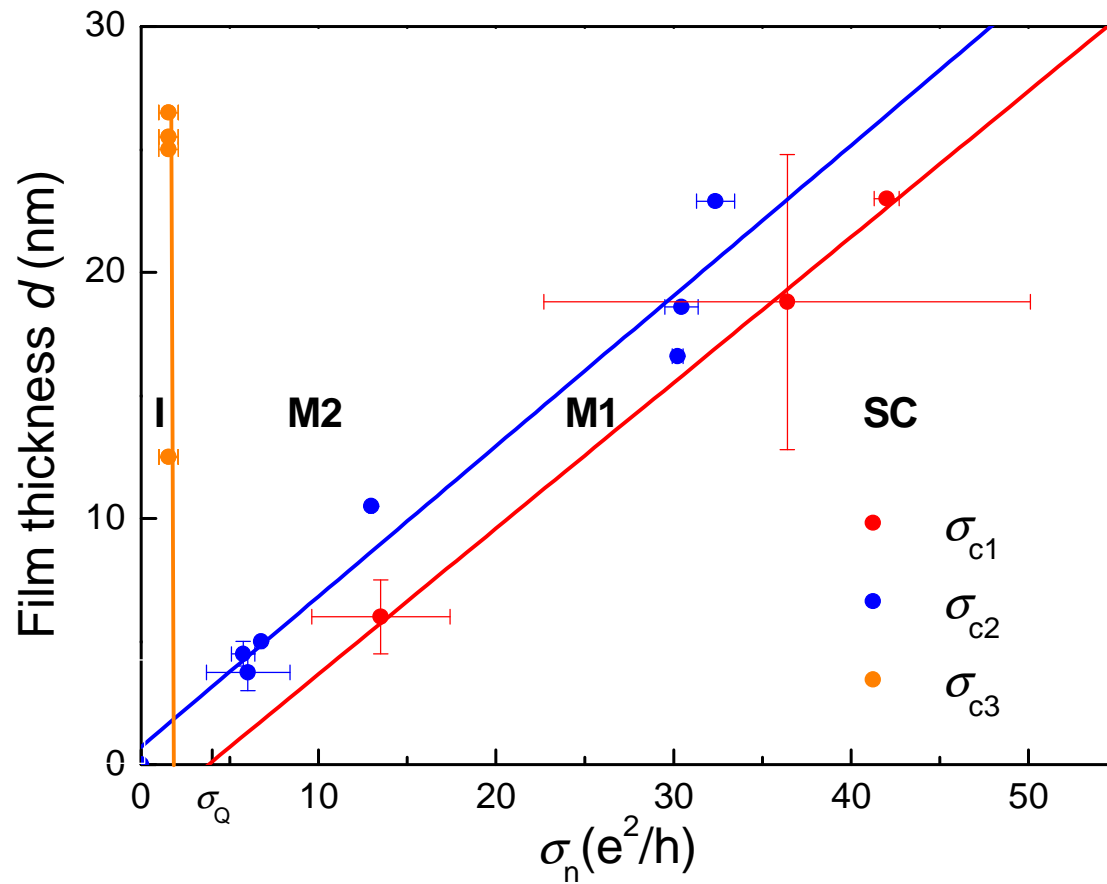


Vanishing of the T_0 and σ_{\min} at $(k_F l)_3 \approx 1$

PHASE DIAGRAM



PHASE DIAGRAM

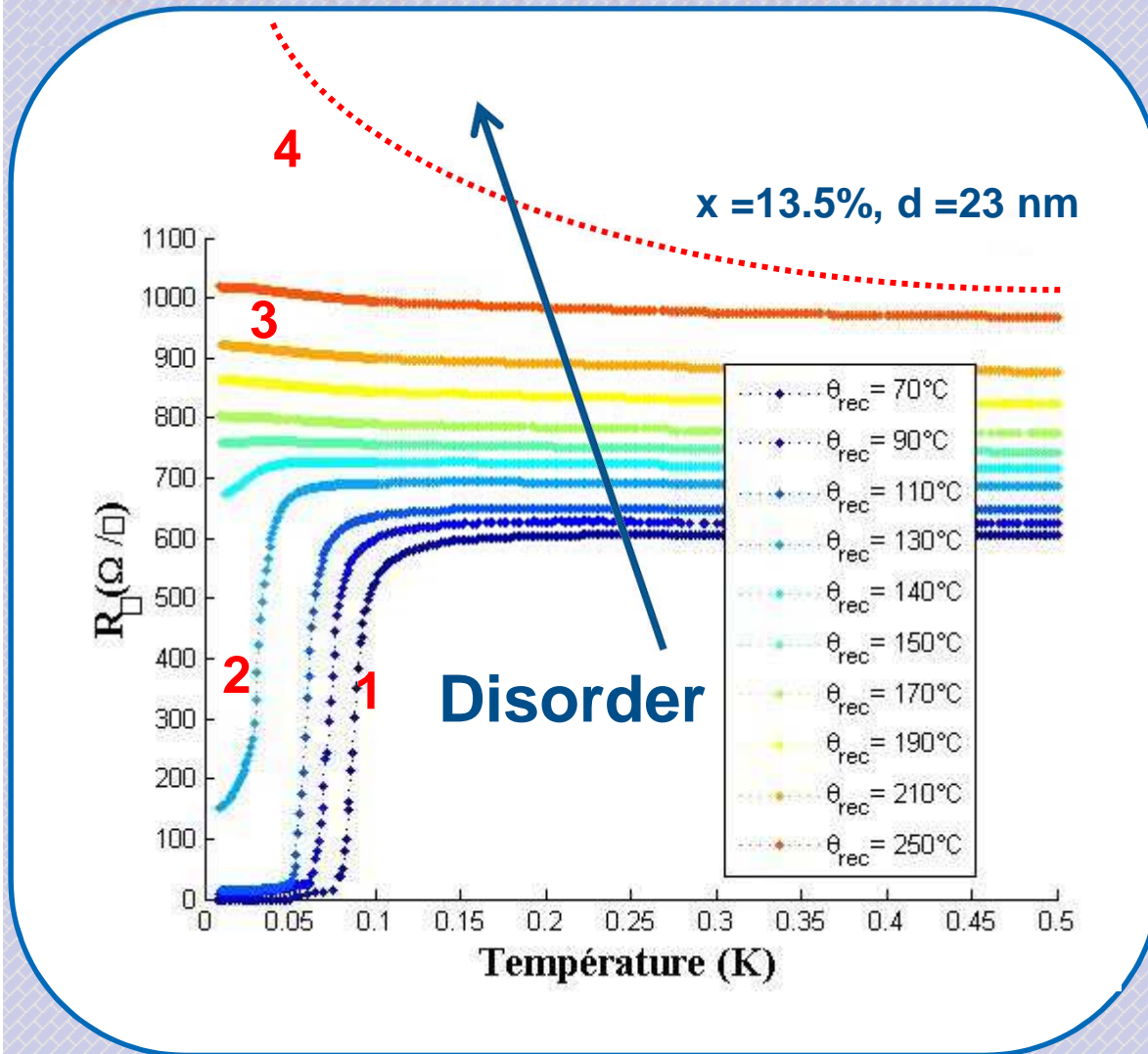


Han et al. Nat. Phys. 10 380 2014

ONSET OF THE INSULATING REGIME

4 DISTINCT REGIMES

At $T \rightarrow 0$



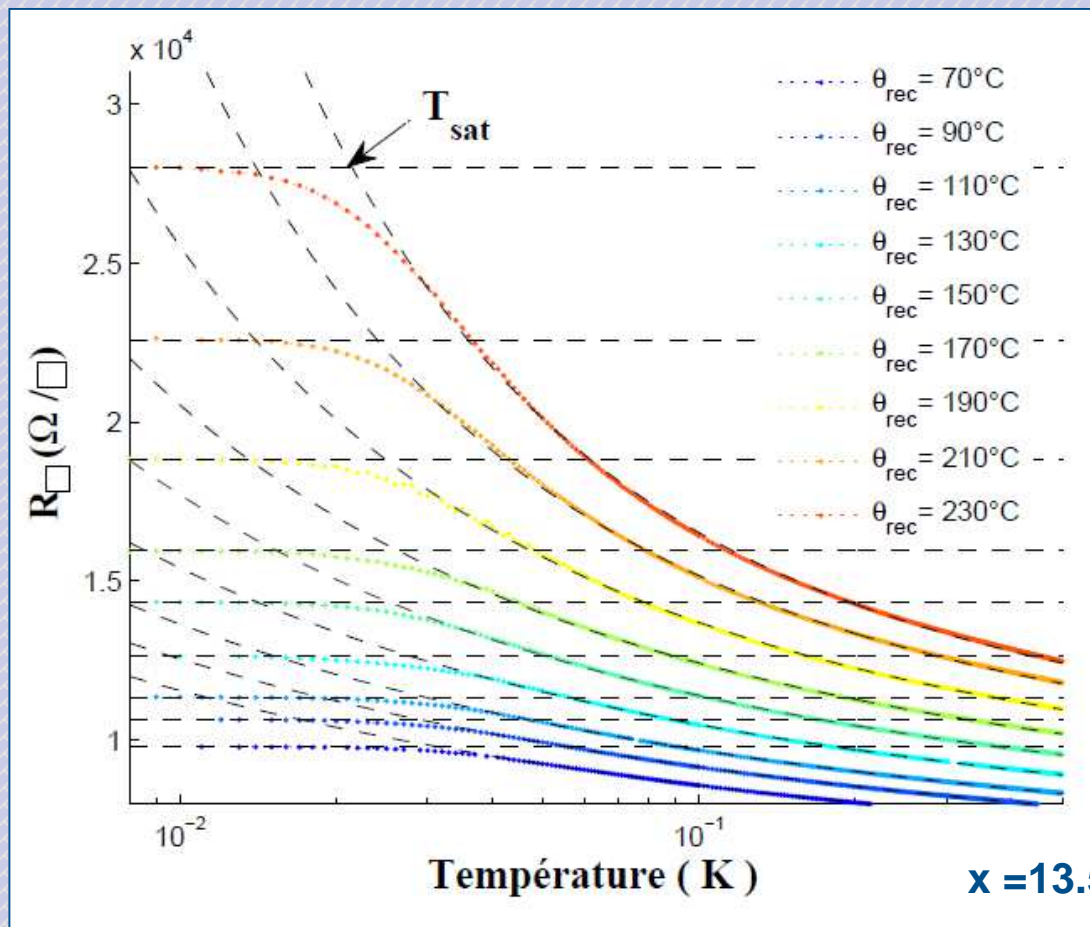
- 1 – Superconductor ($R=0$)
- 2 – Finite R & $TCR > 0$
- 3 – Finite R & $TCR < 0$
- 4 – Insulator

Disorder measured by :

$$R_{\square,N} = R_{\square}(500 \text{ mK})$$

ONSET OF THE INSULATING REGIME

From the Metal 2 phase

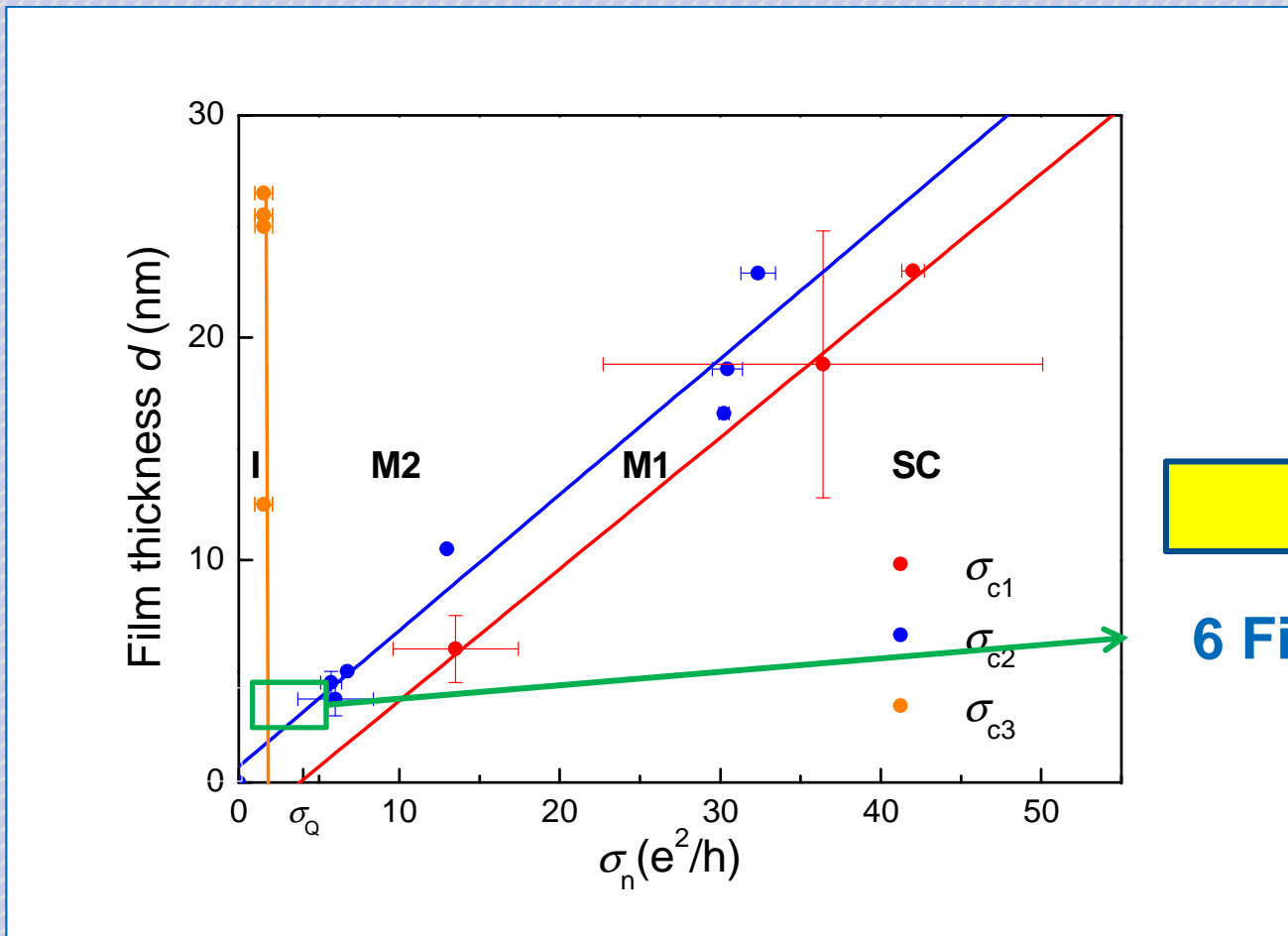


- How does the « Metal 2 » phase evolve towards an insulating regime ?
- Are there any signature of localization in the « Metal 2 » regime ?

$x = 13.5\%$, $d = 5$ nm

SAMPLES

Near the « Metal 2 » - Insulator transition



x = 13.5 %

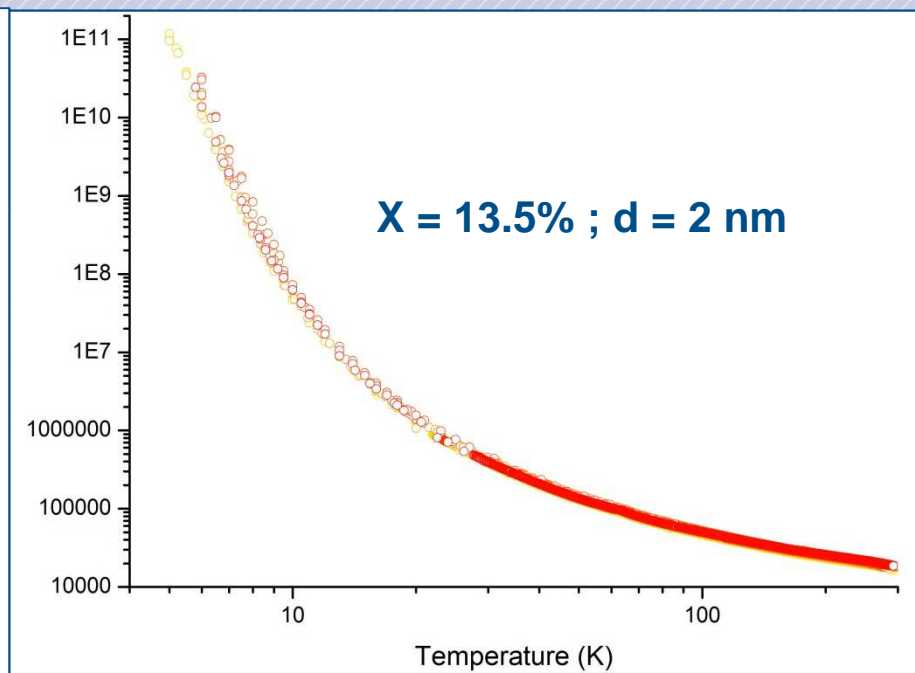
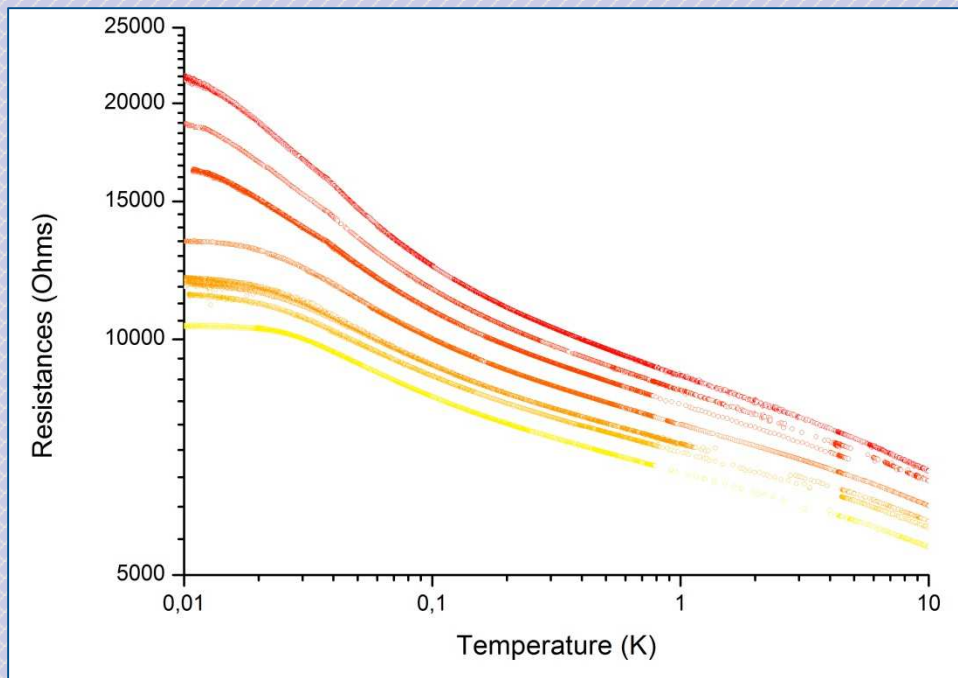
6 Films with $d = [2, 5 \text{ nm}]$

EVOLUTION WITH ANNEALING

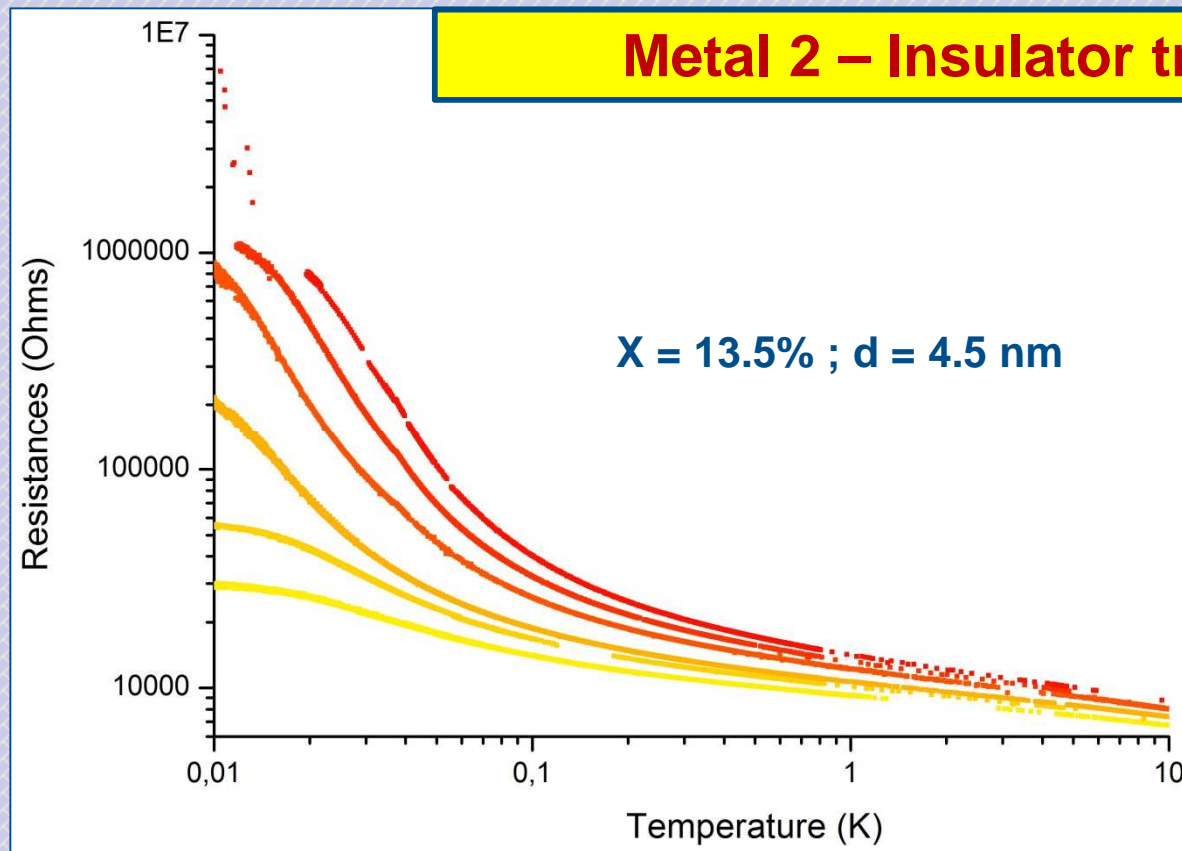
Annealing $\Theta = 70^{\circ}\text{C} - 150^{\circ}\text{C}$

Metal 2

Insulator



EVOLUTION WITH ANNEALING

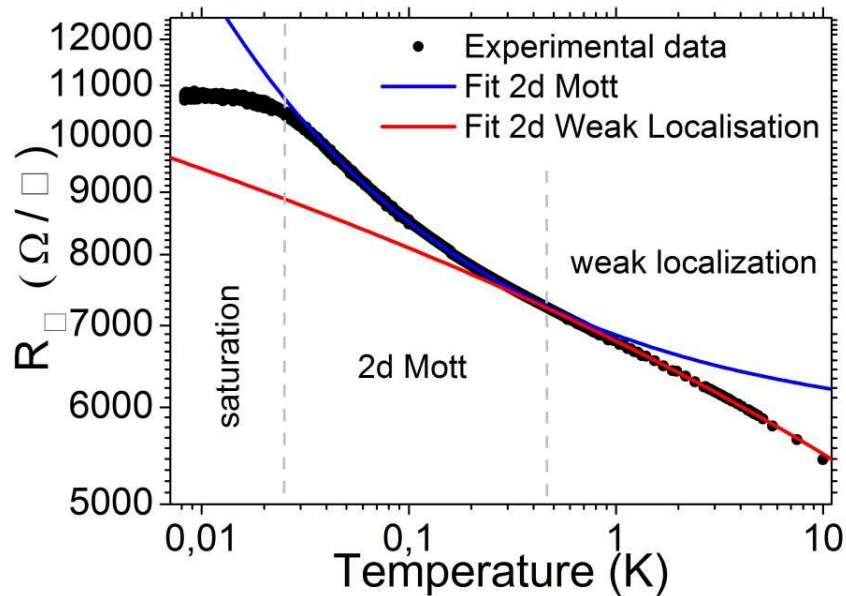


Annealing $\Theta = 70^\circ\text{C} - 150^\circ\text{C}$

R(T) EVOLUTION

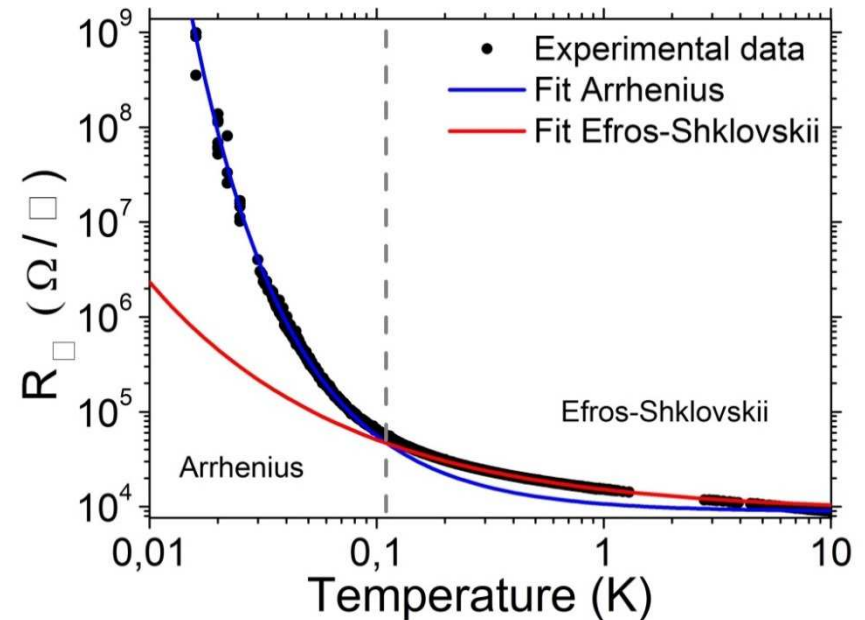
$$R = R_0 e^{-\left(\frac{T}{T_0}\right)^n}$$

Metal 2



Resistance saturating at low temperature

Insulator

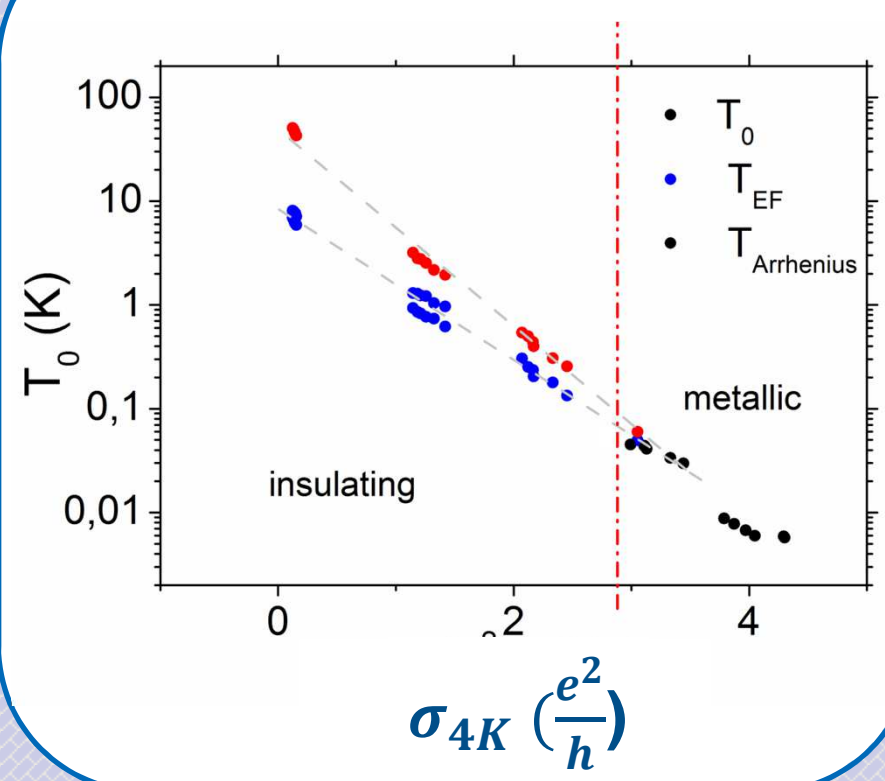
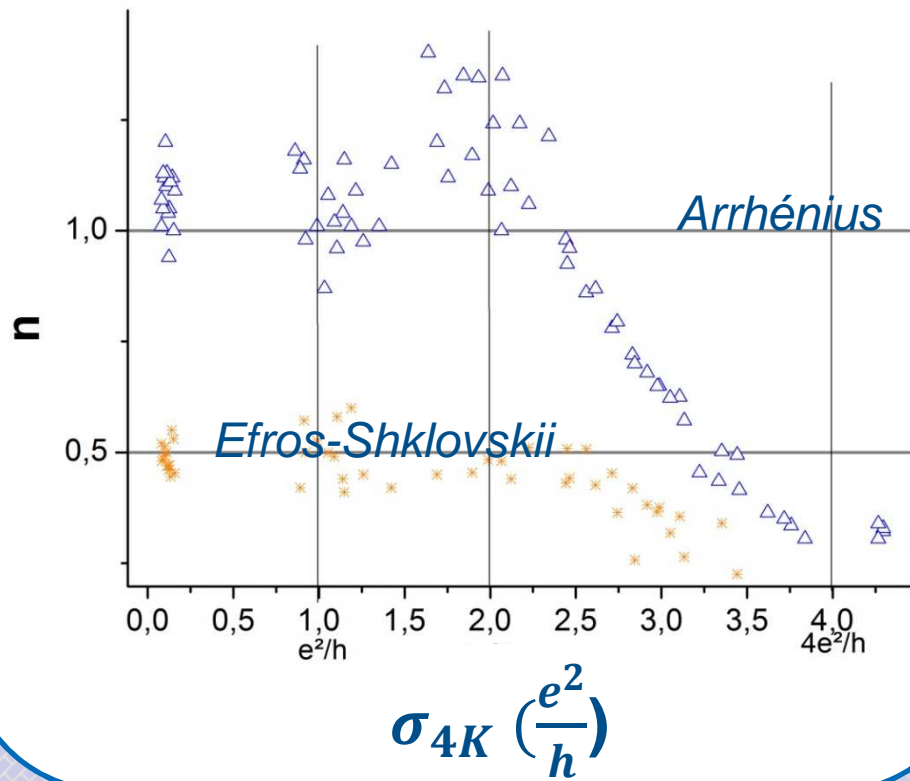


Insulating even at the lowest temperatures

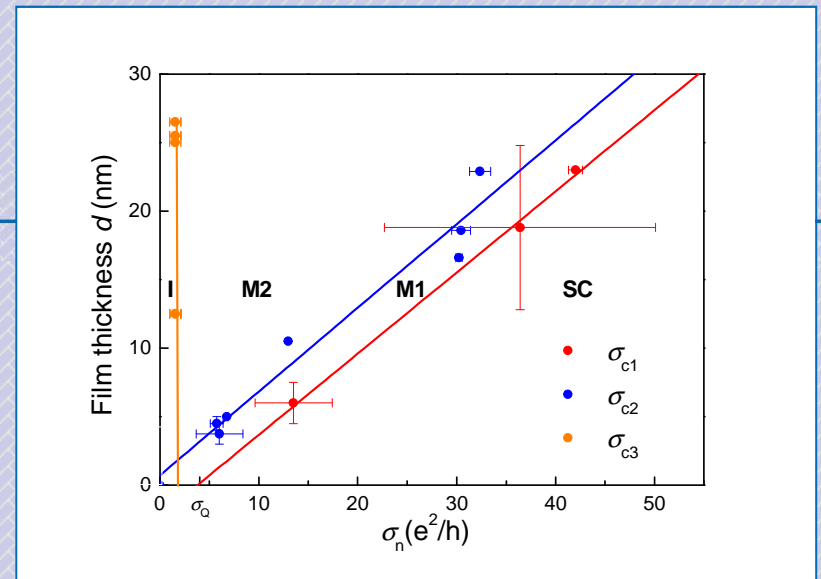
	Weak loc	Strong loc
2d	$\alpha \ln(T)$	$\text{Exp}[(-T/T_0)^n]$

R(T) EVOLUTION

$$R = R_0 e^{-\left(\frac{T}{T_0}\right)^n}$$

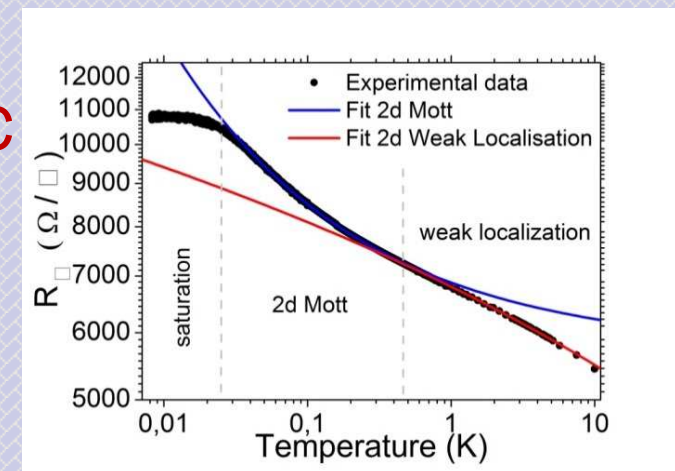


SUMMARY



× 2 dissipative phases observed, possibly linked to inhomogeneous electronic phases

× Gradual evolution from metallic to insulating phase



THANK YOU FOR YOUR ATTENTION !
